

ALARM SURVEILLANCE AND CONTROL SYSTEM
INTERCONNECTION CIRCUIT TESTS
NO. 5 CROSSBAR OFFICES

48

1. GENERAL

1.01 This section describes test procedures for verifying alarm, status, and control leads within No. 5 crossbar offices served by a remote Alarm Surveillance and Control System. These tests may be performed either prior to connection to the Alarm Surveillance and Control center or for trouble detecting purposes in a working configuration.

1.02 This section is reissued for the reasons listed below. Since this is a general revision, revision arrows are not used. This reissue does not affect Equipment Test Lists.

- (a) Part 2 Apparatus, is revised to provide optional test apparatus for verifying condition of scan leads.
- (b) Part 3, Preparation, is revised to add a step for releasing releasable alarms.
- (c) Part 4, Method, is revised to indicate the condition expected on the lead under test.
- (d) To make minor changes as required.

1.03 Only those alarm, status, and control leads extended to the interface and control circuit, SD-28075-01, are covered by this section. Special alarm, status and control leads unique to the central office under test and not extended via the interface and control circuit, are not covered.

1.04 Table A contains scan lead tests A through AS for alarm and status conditions. Table B contains scan lead tests BA through BM for

control and status conditions. The circuits covered by these tests are as follows:

	PAGE
A. Alarm Circuit (SD-25671-01):	
.	5
B. Master Test Frame Jack, Lamp, & Key Circuit (SD-25762-01):	
.	5
C. Combined/Completing Marker Circuit (SD-25550-01/SD-26002-01) First Trial Failure:	
.	6
D. Combined/Completing Marker Circuit (SD-25550-01/SD-26002-01) Second Trial Failure:	
.	6
E. Combined/Completing Marker Circuit (SD-25550-01/SD-26002-01) Link Release:	
.	7
F. Combined/Completing Marker Circuit (SD-25550-01 or SD-26002-01) Transfer Link Release:	
.	7
G. Dial Tone Marker Circuit (SD-25550-01 / SD-26001-01) First Trial Failure:	
.	8
H. Dial Tone Marker Circuit (SD-25550-01 / SD-26001-01) Second Trial Failure:	
.	8
I. Transverter Circuit (SD-25591-01/SD--26010-01, SD-26161-01/	

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	PAGE		PAGE
<i>SD-27809-01, or SD-28085-01)</i> <i>First Trial Failure:</i>	9	<i>Y. PBX-AIOD Miscellaneous Circuit</i> <i>(SD-1C006-01):</i>	17
<i>J. Transverter Circuit (SD-25591</i> <i>01/SD-26010-01, SD-26161-01/</i> <i>SD-27809-01 or SD-28085-01)</i> <i>Second Trial Failure:</i>	10	<i>Z. 1A Line Concentrator Circuit</i> <i>(SD-96536-01):</i>	18
<i>K. Pretranslator Circuit (SD-25568-</i> <i>01) First Trial Failure:</i>	10	<i>AA. 2A Line Concentrator Circuit</i> <i>(SD-94815-01):</i>	18
<i>L. Pretranslator Circuit (SD-25568-</i> <i>01) Second Trial Failure:</i>	11	<i>AB. All Markers/Transverters</i> <i>Busy Circuit (SD-25695-01):</i>	19
<i>M. Trouble Recorder Control and</i> <i>Test Circuit (SD-25572-01):</i>	11	<i>AC. Traffic Register Circuit</i> <i>(SD-25890-01/SD-25892-01):</i>	19
<i>N. Coin Supervisory Circuit</i> <i>(SD-25736-01):</i>	12	<i>AD. Sender Group Busy Circuit</i> <i>(SD-25500-01/SD-27638-01/</i> <i>SD-25890-01):</i>	20
<i>O. Automatic Monitor, Register,</i> <i>Sender Test Circuit (SD-25680-</i> <i>01):</i>	12	<i>AE. 101 ESS Maintenance Center</i> <i>(SD-1H052-01):</i>	20
<i>P. Line Insulation Test Control</i> <i>Circuit (SD-25796-01):</i>	13	<i>AF. 3A Auxiliary Processor ETS</i> <i>(SD-28118-01):</i>	21
<i>Q. Dial Tone Speed Register</i> <i>Circuit (SD-96403-01):</i>	13	<i>AG. Power Distribution Interface</i> <i>ETS (SD-28114-01) Watch</i> <i>Dog Timer Failure:</i>	21
<i>R. 4A Traffic Usage Recorder</i> <i>Circuit (SD-95738-01):</i>	14	<i>AH. Power Distribution Interface</i> <i>ETS (SD-28114-01) AIOD</i> <i>Translator Stuck:</i>	22
<i>S. Maintenance Data Transmitter</i> <i>Circuit (SD-28111-01):</i>	14	<i>AI. Program Controlled Trans-</i> <i>verter Circuit (SD-28085-01):</i>	23
<i>T. Line Load Control Circuit</i> <i>(SD-96387-01):</i>	15	<i>AJ. Permanent Signal Alarm Circuit</i> <i>(SD-26135-01):</i>	23
<i>U. MF Current Supply Circuit</i> <i>(SD-95391-01):</i>	15	<i>AK. Master Test Frame Jack,</i> <i>Lamp, and Key Circuit</i> <i>(SD-25762-01):</i>	24
<i>V. Message Register Power</i> <i>Supply Circuit (SD-25770-01):</i>	16	<i>AL. Alarm Sending Circuit</i> <i>(SD-95417-01):</i>	24
<i>W. Line Identifier Power Supply</i> <i>Circuit (SD-27700-01):</i>	16	<i>AM. AMA Recorder Transfer Circuit</i> <i>(SD-28076-01):</i>	24
<i>X. Extension Alarm Circuit</i> <i>(SD-95484-01):</i>	17		

	PAGE		PAGE
AN. Combined/Completing Marker Circuit (SD-25550-01/ SD-26001-01) Marker Peg Count:	25	BJ. Master Test Frame Jack, Lamp, & Key Circuit (SD-25762-01) Control Functions:	32
AO. Dial Tone Marker Circuit (SD-25550-01 / SD-26001-01) Marker Peg Count:	25	BK. AMA Recorder Transfer Circuit (SD-28076-01):	32
AP. Electric Dial Tone Speed Register Circuit (SD-3B504-01):	26	BL. Interface and Control Circuit (SD-28075-01) Stuck Sender Hold Feature:	33
AQ. AIOD Transverter Connector Circuit (SD-99320-01):	26	BM. Line Concentrator Identifier Circuit (SD-95964-01):	33
AR. Line Connector Identifier (SD-95964-01):	27	1.05 The statement between the asterisks (*_*) after action or verification statements is added to clarify the function being simulated in the test procedures.	
AS. No. 1 Trunk Concentrator (SD-97595-01):	27	2. APPARATUS	
COMMAND AND STATUS LEAD TESTS—TABLE B		All Tests	
BA. Dial Tone Marker Circuit (SD-25550-01 SD-26001-01):	27	2.01 KS-14510 L3 volt-ohmmeter, equipped with L3 test probes or POLAR PROBE* CMC 5334A (used to verify that ground is present at the interface and control terminal strip terminals). Do not use test receiver.	
BB. Combined/Completing Marker Circuit (SD-25550-01/ SD-26002-01):	28	*Trademark Communications Manufacturing Co.	
BC. Transverter Circuit (SD-25591-01/SD-26010-01, SD-26161-01/ SD-27809-01):	29	2.02 322A (make-busy) plugs as required.	
BD. Pretranslator Circuit (SD-25568-01):	29	2.03 Blocking and insulating tools as required. Use tools and apply as covered in Section 069-020-801.	
BE. Trouble Recorder Control Circuit (SD-25572-01):	30	2.04 Testing cords as required, 893 cord, 6 feet long, equipped with two 360A tools (1W13B cord), one 419A tool, and one KS-6278 connecting clip (used to connect ground to relay contacts on apparatus side of circuit under test).	
BF. Line Insulation Test Control Circuit (SD-25796-01):	30	2.05 Testing cords as required, 893 cord, 6 feet long, equipped with two 360A tools (1W13B cord), and two KS-6278 connecting clips (used to establish connections to terminal strip terminals of the interface and control circuit).	
BG. Traffic Usage Recorder Circuit (SD-95738-01):	31	2.06 Testing cords as required, 893 cord, 6 feet long, equipped with two 360A tools (1W13B cord), one 670A tool, and one KS-6278 connecting	
BH. Interface and Control Circuit (SD-28075-01):	31		
BI. 3A Auxiliary Processor (SD-28118-01):	31		

SECTION 218-759-501

clip (used to connect ground to non-wire-spring-relay windings on apparatus side of circuit under test).

3. PREPARATION

3.01 If office under test is on-line to a remote alarm surveillance and control center, notify center that local tests are to be made. Indicate what equipment is to be tested, when testing will start, and the estimated time of completion of tests.

3.02 From control center, determine if any remote controls have been applied, eg, equipment made busy, recorder transferred, etc. Apply local controls. At MTF jack, lamp, and key circuit, momentarily operate REL key.

3.03 At the conclusion of testing, notify remote Alarm Surveillance and Control center. Restore all keys and switches to position found at start of test.

STEP	ACTION	VERIFICATION
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All Tests

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|----|--|------------------------|
| 1 | At MTF jack, lamp, and key circuit—
Momentarily operate REM key to place office alarms in remote (unattended) mode. | REM lamp lighted. |
| 2 | At MTF jack, lamp, and key circuit—
Momentarily operate MAR key.
Momentary operation of the MAR key will release a locked in alarm, provided the trouble condition causing the alarm has been corrected. | |
| 3a | If any control function has been initiated at control center—
At MTF, jack, lamp, and key circuit—
Momentarily operate REL key. | CTL lamp extinguished. |

Note: If CAL lamp lighted—control center requests a telephone call from the local office. Contact control center for instruction.

4. METHOD**SCAN LEAD TESTS—TABLE A****A. Alarm Circuit (SD-25671-01)**

STEP	ACTION	VERIFICATION
4	At interface and control circuit— Connect test probe as required, to terminal strip terminal as specified in Table A, Test A.	If an alarm is locked-in to scan lead under test— Ground present at terminal strip terminal.
5b	If an alarm is locked-in to scan lead under test— At MTF jack, lamp, and key circuit— Momentarily operate MAR key.	At interface and control circuit— Ground removed from terminal strip terminal.
6	At alarm circuit under test— Block operated relay associated with scan lead under test as specified in Table A, Test A.	At interface and control circuit— Ground present at terminal strip terminal.
7	At alarm circuit under test— Remove blocking tool placed in Step 6.	
8	At interface and control circuit— Disconnect test probe from terminal strip terminal.	
9	Repeat Steps 4 through 8 as required for each scan lead under test as specified in Table A, Test A.	

B. Master Test Frame Jack, Lamp, and Key Circuit (SD-25762-01)

4	At interface and control circuit— Connect test probe as required, to terminal strip terminal as specified in Table A, Test B.	If an alarm is locked-in to scan lead under test— Ground present at terminal strip terminal.
5b	If an alarm is locked in to scan lead under test— At MTF jack, lamp, and key circuit— Momentarily operate MAR key.	At interface and control circuit— Ground removed from terminal strip terminal.
6	At circuit under test— Block operated relay associated with scan lead under test as specified in Table A, Test B.	At interface and control circuit— Ground present at terminal strip terminal.
7	At circuit under test— Remove blocking tool placed in Step 6.	

SECTION 218-759-501

- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 4 through 8 as required for each scan lead under test as specified in Table A, Test B.

C. Combined/Completing Marker Circuit (SD-25550-01/SD-26002-01) First Trial Failure

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test C.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At marker circuit under test—
Connect ground to relay contact associated with scan lead under test as specified in Table A, Test C.
At interface and control circuit—
Ground present at terminal strip terminal.
- 7 At marker circuit under test—
Disconnect ground placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 5 through 8 for each scan lead under test as specified in Table A, Test C, for each marker circuit.

D. Combined/Completing Marker Circuit (SD-25550-01/SD-26002-01) Second Trial Failure

- 4 At interface and control circuit—
Connect test probe as required to terminal strip terminal as specified in Table A, Test D.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At marker circuit under test—
Connect ground to relay contact associated with scan lead under test as specified in Table A, Test D.
At interface and control circuit—
Ground present at terminal strip terminal.
Single digit 2nd trial failure register for combined/completing markers advances one registration.

- 7 At marker circuit under test—
Disconnect ground placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 4 through 8 for each lead under test as specified in Table A, Test D, for each marker circuit.

**E. Combined/Completing Marker Circuit (SD-25550-01/
SD-26002-01) Link Release**

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test E.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At marker circuit under test—
Connect ground to relay contact associated with scan lead under test as specified in Table A, Test E.
At interface and control circuit—
Ground present at terminal strip terminal.
- 7 At marker circuit under test—
Disconnect ground placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test E, for each marker circuit.

**F. Combined/Completing Marker Circuit (SD-25550-01
or SD-26002-01) Transfer Link Release**

- 4 At interface and control circuit—
Connect test probe as required to terminal strip terminal as specified in Table A, Test F.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.

SECTION 218-759-501

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| 6 | At marker circuit under test—
Connect ground to relay contact associated with scan lead under test as specified in Table A, Test F. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At marker circuit under test—
Disconnect ground placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test F, for each marker circuit. | |

G. Dial Tone Marker Circuit (SD-25550-01/SD-26001-01) First Trial Failure

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| 4 | At interface and control circuit—
Connect test probe as required to terminal strip terminal as specified in Table A, Test G. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At marker circuit under test—
Connect ground to relay contact associated with scan lead under test as specified in Table A, Test G. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At marker circuit under test—
Disconnect ground placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test G, for each marker circuit. | |

H. Dial Tone Marker Circuit (SD-25550-01/SD-26001-01) Second Trial Failure

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| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test H. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
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| 5b | If alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At marker circuit under test—
Connect ground to relay contact associated
with scan lead under test as specified in Table
A, Test H. | At interface and control circuit—
Ground present at terminal strip terminal.
Single digit 2nd trial failure register for dial
tone markers advances one registration. |
| 7 | At marker circuit under test—
Disconnect ground placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip
terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead
under test as specified in Table A, Test H,
for each marker circuit. | |

**I. Transverter Circuit (SD-25591-01/SD-26010-01,
SD-26161-01/SD-27809-01 or SD-28085-01) First
Trial Failure**

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| 4 | At interface and control circuit—
Connect test probe as required, to terminal
strip terminal as specified in Table A, Test
I. | If an alarm is locked-in to scan lead under
test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under
test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At transverter circuit under test—
Connect ground to relay contact associated
with scan lead under test as specified in Table
A, Test I. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At transverter circuit under test—
Disconnect ground placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip
terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead
under test as specified in Table A, Test I,
for each Transverter. | |

SECTION 218-759-501

**J. Transverter Circuit (SD-25591-01/SD-26010-01,
or SD-26161-01/SD-27809-01 or SD-28085-01)
Second Trial Failure**

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|----|---|--|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test J. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At transverter circuit under test—
Connect ground to relay contact associated with scan lead under test as specified in Table A, Test J. | At interface and control circuit—
Ground present at terminal strip terminal.
Single digit 2nd trial register for transverters advances one registration. |
| 7 | At transverter circuit under test—
Disconnect ground placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test J. | |

K. Pretranslator Circuit (SD-25568-01) First Trial Failure

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| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test K. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At pretranslator circuit under test—
Connect ground to relay contact associated with scan lead under test as specified in Table A, Test K. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At pretranslator circuit under test—
Disconnect ground placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |

- 9 Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test K, for each pretranslator.

L. Pretranslator Circuit (SD-25568-01) Second Trial Failure

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| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test L. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At pretranslator circuit under test—
Connect ground to relay contact associated with scan lead under test as specified in Table A, Test L. | At interface and control circuit—
Ground present at terminal strip terminal.
Single digit 2nd trial failure register for pretranslators advances one registration. |
| 7 | At pretranslator circuit under test—
Disconnect ground placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test L, for each pretranslator. | |

M. Trouble Recorder Control and Test Circuit (SD-25572-01)

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| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test M. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At trouble recorder control circuit under test—
Connect ground to relay contact or block operated relay associated with scan lead under test as specified in Table A, Test M. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At trouble recorder control circuit—
Disconnect ground or remove blocking tool placed in Step 6. | |

SECTION 218-759-501

- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test M.

N. Coin Supervisory Circuit (SD-25736-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test N.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At coin supervisory circuit under test—
Connect ground to relay contact or block operated relay associated with scan lead under test as specified in Table A, Test N.
At interface and control circuit—
Ground present at terminal strip terminal.
- 7 At coin supervisory circuit under test—
Disconnect ground or remove blocking tool placed in Step 6.
- 8 At interface control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test N.

O. Automatic Monitor, Register, Sender Test Circuit (SD-25680-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test O.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At automatic monitor, register, sender circuit under test—
Connect ground to relay contact or block operated relay associated with scan lead under test as specified in Table A, Test N.
At interface and control circuit—
Ground present at terminal strip terminal.

- 7 At automatic monitor, register, sender circuit under test—
Disconnect ground or remove blocking tool placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

P. Line Insulation Test Control Circuit (SD-25796-01)

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| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test P. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At line insulation test control circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test P. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At line insulation test control circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |

Q. Dial Tone Speed Register Circuit (SD-96403-01)

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| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test Q. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If a alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At dial tone speed register circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test Q. | At interface and control circuit—
Ground present at terminal strip terminal. |

SECTION 218-759-501

- 7 At dial tone speed register circuit under test—
Disconnect ground or remove blocking tool placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

R. 4A Traffic Usage Recorder Circuit (SD-95738-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test R. If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At 4A traffic usage recorder circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test R. At interface and control circuit—
Ground present at terminal strip terminal.
- 7 At 4A traffic usage record circuit under test—
Disconnect ground or remove blocking tool placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

S. Maintenance Data Transmitter Circuit (SD-28111-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test S. If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At maintenance data transmitter circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test S. At interface and control circuit—
Ground present at terminal strip terminal.

- 7 At maintenance data transmitter circuit under test—
Disconnect ground or remove blocking tool placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

T. Line Load Control Circuit (SD-96387-01)

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|----|--|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test T. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At line load control circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test T. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At line load control circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |

U. MF Current Supply Circuit—(SD-95391-01)

- | | | |
|----|--|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test U. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At MF current supply circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test U. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At MF current supply circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |

SECTION 218-759-501

- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

V. Message Register Power Supply Circuit (SD-25770-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test V.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At message register power supply circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test V.
At interface and control circuit—
Ground present at terminal strip terminal.
- 7 At message register power supply circuit under test—
Disconnect ground or remove blocking tool placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

W. Line Identifier Power Supply Circuit (SD-27700-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test W.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At line identifier power supply circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test W.
At interface and control circuit—
Ground present at terminal strip terminal.
- 7 At line identifier power supply circuit under test—
Disconnect ground or remove blocking tool placed in Step 6.

- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

X. Extension Alarm Circuit (SD-95484-01)

- | | | |
|----|--|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test X. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At extension alarm circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test X. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At extension alarm circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test X. | |

Y. PBX-AIOD Miscellaneous Circuit (SD-1C006-01)

- | | | |
|----|---|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test Y. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At PBX-AIOD circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test Y. | |
| 7 | At PBX-AIOD circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |

SECTION 218-759-501

- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test Y.

Z. 1A Line Concentrator Circuit (SD-96536-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test Z.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At 1A line concentrator under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test Z.
At interface and control circuit—
Ground present at terminal strip terminal.
- 7 At 1A line concentrator under test—
Disconnect ground or remove blocking tool placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test Z.

AA. 2A Line Concentrator Circuit—(SD-94815-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AA.
If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.
- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At 2A line concentrator circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AA.
At interface and control circuit—
Ground present at terminal strip terminal.

- 7 At 2A line concentrator circuit under test—
Disconnect ground or remove blocking tool
placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip
terminal.
- 9 Repeat Steps 4 through 8 for each scan lead
under test as specified in Table A, Test AA.

AB. All Markers/Transverters Busy Circuit (SD-25695-01)

- | | | |
|----|--|--|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal
strip terminal as specified in Table A, Test
AB. | If an alarm is locked-in to scan lead under
test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under
test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At marker/transverter busy circuit under
test—
Connect ground or block operated relay
associated with scan lead under test as specified
in Table A, Test AB. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At marker/transverter busy circuit under
test—
Disconnect ground or remove blocking tool
placed in Step 6. | |
| 7 | At interface and control circuit—
Disconnect test probe from terminal strip
terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead
under test as specified in Table A, Test AB. | |

AC. Traffic Register Circuit (SD-25890-01/SD-25892-01)

- | | | |
|----|---|--|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal
strip terminal as specified in Table A, Test
AC. | If an alarm is locked-in to scan lead under
test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under
test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |

SECTION 218-759-501

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|---|--|---|
| 6 | At traffic register circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AC. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At traffic register circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AC. | |

**AD. Sender Group Busy Circuit (SD-25500-01/
SD-27638-01, SD-25890-01)**

- | | | |
|----|---|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AD. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At sender group busy circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AD. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At sender group busy circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AD. | |

AE. 101 ESS Maintenance Center (SD-1H052-01)

- | | | |
|----|---|---|
| 4 | At interface control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AE. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |

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|---|---|---|
| 6 | At 101 ESS maintenance center control unit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AE. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At 101 ESS maintenance center control unit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AE. | |

AF. 3A Auxiliary Processor—ETS (SD-28118-01)

- | | | |
|---|--|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AF. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5 | If an alarm is locked-in to scan lead under test—
At system status panel—
Momentarily operate AR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At 3A auxiliary processor circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AF. | At Interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At 3A auxiliary processor circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AF. | |

AG. Power Distribution Interface Circuit ETS (SD-28114-01) Watch Dog Timer Failure

- | | | |
|---|---|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AG. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
|---|---|---|

SECTION 218-759-501

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|----|--|---|
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At power distribution interface circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AG. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At power distribution interface circuit under Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AG. | |

**AH. Power Distribution Interface Circuit ETS
(SD-28114-01) AIOD Translator Stuck**

- | | | |
|----|--|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AH. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At power distribution interface circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AH. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At power distribution interface circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AH. | |

AI. Program Controlled Transverter Circuit (SD-28085-01)

- | | | |
|----|--|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AI. | If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At program controlled transverter circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AI. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At program controlled transverter circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under Test as specified in Table A, Test AI. | |

AJ. Permanent Signal Alarm Circuit (SD-26135-01)

- | | | |
|----|--|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AJ. | If an alarm is locked in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At permanent signal alarm circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AJ. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | At permanent signal alarm circuit under test—
Disconnect ground or remove blocking tool placed in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |

SECTION 218-759-501

9 Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AJ.

AK. Master Test Frame Jack, Lamp, and Key Circuit (SD-25762-01)

4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AK.

If an alarm is locked-in to scan lead test—
Ground present at terminal strip terminal.

5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key.

At interface and control circuit—
Ground removed from terminal strip terminal.

6 Operate key associated with scan lead under test as specified in Table A, Test AK.

At interface and control circuit—
Ground present at terminal strip terminal.

7 At master test frame jack, lamp, and key circuit—
Restore keys to position for normal attended operation.

8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

9 Repeat Steps 4 through 8 for each scan lead under Test as specified in Table A, Test AK.

AL. Alarm Sending Circuit (SD-95417-01)

4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AL.

5 At MTF, jack, lamp, and key circuit—
Operate alarm sending transfer key to transfer position.

At interface and control circuit—
Ground present at terminal strip terminal.

6 At MTF, jack, lamp, and key circuit—
Restore alarm sending transfer to non-transferred position. Momentarily operate RS key.

At interface and control circuit—
Ground removed from terminal strip terminal.

7 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

AM. AMA Recorder Transfer Circuit (SD-28076-01)

4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table A, Test AM.

If an alarm is locked-in to scan lead under test—
Ground present at terminal strip terminal.

- 5b If an alarm is locked-in to scan lead under test—
At jack, lamp, and key circuit—
Momentarily operate MAR key. At interface and control circuit—
Ground removed from terminal strip terminal.
- 6 At recorder transfer circuit under test—
Connect ground or block operated relay associated with scan lead under test as specified in Table A, Test AM. At interface and control circuit—
Ground present at terminal strip terminal.
- 7 At recorder transfer circuit under test—
Disconnect ground or remove blocking tool placed in Step 6.
- 8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 9 Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AM.
- AN. Combined/Completing Marker Circuit (SD-25550-01/ SD-26002-01) Marker Peg Count**
- 4 At interface and control circuit—
Connect test probe to terminal strip terminal as specified in Table A, Test AN.
- 5 At combined/completing marker circuit under test—
Block operated relay associated with scan lead under test as specified in Table A, Test AN. At interface and control circuit—
Ground present at terminal strip terminal.
- 6 Release relay operated in Step 5. Ground removed from terminal strip terminal.
- 7 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 8 Repeat Steps 4 through 7 for each scan lead under Test as specified in Table A, Test AN.
- AO. Dial Tone Marker Circuit (SD-25550-01/ SD-26001-01) Marker Peg Count**
- 4 At interface and control circuit—
Connect test probe to terminal strip terminal as specified in Table A, Test AO.
- 5 At dial tone marker circuit under test—
Block operated relay associated with scan lead under test as specified in Table A, Test AO. At interface and control circuit—
Ground present at terminal strip terminal.
- 6 Release relay operated in Step 5. Ground removed from terminal strip terminal.

SECTION 218-759-501

7 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

8 Repeat Steps 4 through 7 for each scan lead under test as specified in Table A, Test AO.

AP. Electronic Dial Tone Speed Register Circuit (SD-3B504-01)

4 At interface and control circuit—
Connect test probe to terminal strip terminal specified in Table A, Test AP.

If an alarm locked-in to scan lead under test—
Ground present at terminal strip terminal.

5b If an alarm is locked-in to scan lead under test—
At master test frame jack, lamp, and key circuit—
Momentarily operate MAR key.

At interface and control circuit—
Ground removed from terminal strip terminal.

6 At electronic dial tone speed register circuit—
Connect ground to relay contact as specified in Table A, Test AP.

At interface and control circuit—
Ground present at terminal strip terminal.

7 Disconnect ground placed in Step 6.

8 At interface and control circuit—
Disconnect test probe.

AQ. AIOD Transverter Connector Circuit (SD-99320-01)

3 At interface and control circuit—
Connect test probe to terminal strip terminal as specified in Table A, Test AQ.

If an alarm locked-in to scan lead under test—
Ground present at terminal strip terminal.

5b If an alarm is locked-in to scan lead under test—
At master test frame jack, lamp, and key circuit—
Momentarily operate MAR key.

At interface and control circuit—
Ground removed from terminal strip terminal.

6 At AIOD transverter connector—
Connect ground to relay contact specified in Table A, Test AQ.

At interface and control circuit—
Ground present at terminal strip terminal.

7 Disconnect ground placed in Step 6.

8 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

AR. Line Concentrator Identifier (SD-95964-01)

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|----|--|--|
| 4 | At interface and control circuit—
Connect test probe to terminal strip terminal as specified in Table A, Test AR. | If an alarm locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm locked-in to scan lead under test—
At master test frame jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At line concentrator identifier circuit under test—
Block operated relay associated with scan lead under test as specified in Table A, Test AR. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | Release relay operated in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |

AS. No. 1 Trunk Concentrator (SD-97595-01)

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|----|--|--|
| 4 | At interface and control circuit—
Connect test probe to terminal strip terminal as specified in Table A, Test AS. | If an alarm locked-in to scan lead under test—
Ground present at terminal strip terminal. |
| 5b | If an alarm locked-in to scan lead under test—
At master test frame jack, lamp, and key circuit—
Momentarily operate MAR key. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 6 | At No. 1 trunk concentrator under test—
Block operated relay associated with scan lead under test as specified in Table A, Test AS. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 7 | Release relay operated in Step 6. | |
| 8 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 9 | Repeat Steps 4 through 8 for each scan lead under test as specified in Table A, Test AS. | |

COMMAND AND STATUS LEAD TESTS—TABLE B**BA. Dial Tone Marker Circuit (SD-25550-01/
SD-26001-01)**

- | | | |
|---|--|---|
| 4 | At interface and control circuit—
Connect test probe to terminal strip terminal as specified in Table B, Test BA. | If circuit under test is made busy—
Ground present at terminal strip terminal. |
|---|--|---|

SECTION 218-759-501

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|----|---|---|
| 5 | At master test frame, jack, lamp and key circuit—
At circuit under test—
Insert make-busy plug in MB jack as specified in Table B, Test BA. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 6 | Remove MB plug placed in Step 5. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 7 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 8 | At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BA. | At circuit under test—
MB relay operates. |
| 9 | At interface and control circuit—
Disconnect ground placed in Step 8. | |
| 10 | Repeat Steps 4 through 9 for each scan lead under test as specified in Table B, Test BA. | |

**BB. Combined/Completing Marker Circuit
(SD-25550-01/SD-26002-01)**

- | | | |
|----|---|---|
| 4 | At interface and control circuit—
Connect test probe as required to terminal strip terminal as specified in Table B, Test BB. | If circuit under test is made busy—
Ground present at terminal strip terminal. |
| 5 | At master test frame, jack, lamp, and key circuit—
At circuit under test—
Make circuit under test busy by inserting MB plug in MB jack. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 6 | Removed MB plug placed in Step 5. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 7 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 8 | At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BB. | At circuit under test—
MB relay operates. |
| 9 | At interface and control circuit—
Disconnect ground placed in Step 8. | |
| 10 | Repeat Steps 4 through 9 for each scan lead under test as specified in Table B, Test BB. | |

**BC. Transverter Circuit (SD-25591-01/SD-26010-01,
SD-26161-01/SD-27809-01)**

- | | | |
|----|---|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table B, Test BC. | If circuit under test is made busy—
Ground present at terminal strip terminal. |
| 5 | At master test frame, jack, lamp, and key circuit—
At circuit under test—
Make circuit under test busy by inserting MB plug in MB jack. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 6 | Remove MB plug placed in Step 5. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 7 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 8 | At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BC. | At circuit under test—
RB relay operates. |
| 9 | At interface and control circuit—
Disconnect ground placed in Step 8. | |
| 10 | Repeat Steps 4 through 9 for each scan lead under test as specified in Table B, Test BC. | |

BD. Pretranslator (SD-25568-01)

- | | | |
|---|--|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table B, Test BD. | If circuit under test is made busy—
Ground present at terminal strip terminal. |
| 5 | At master test frame jack, lamp, and key circuit—
At circuit under test—
Make circuit under test busy by inserting MB plug in MB jack. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 6 | Remove MB plug placed in Step 5. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 7 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 8 | At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BD. | At circuit under test—
MB relay operates. |

SECTION 218-759-501

- 9 At interface and control circuit—
Disconnect ground placed in Step 8.
- 10 Repeat Steps 4 through 9 for each scan lead under test as specified in Table B, Test BD.

BE. Trouble Recorder Control Circuit (SD-25572-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table B, Test BE.
If circuit under test is made busy—
Ground present at terminal strip terminal.
- 5 At master test frame, jack, lamp, and key circuit—
Make circuit under test busy by inserting MB plug in TR MB jack.
At interface and control circuit—
Ground present at terminal strip terminal.
- 6 Remove MB plug placed in Step 5.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 7 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 8 At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BE.
At circuit under test—
ROS relay operates.
- 9 At interface and control circuit—
Disconnect ground placed in Step 8.
- 10 Repeat Steps 4 through 9 for each scan lead under test as specified in Table B, Test BE.

BF. Line Insulation Test Circuit (SD-25796-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table B, Test BF.
If circuit under test is made busy—
Ground present at terminal strip terminal.
- 5 At line insulation test circuit—
Operate TS Key.
At interface and control circuit—
Ground present at terminal strip terminal.
- 6 At line insulation test circuit—
Restore TS key operated in Step 5.
At interface and control circuit—
Ground removed from terminal strip terminal.
- 7 At interface and control circuit—
Disconnect test probe from terminal strip terminal.
- 8 At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BF.
At circuit under test—
RS relay operates.

- 9 At interface and control circuit—
Disconnect ground place in Step 8.
- 10 Repeat Steps 4 through 9 for each scan lead
under test as specified in Table B, Test BF.

BG. Traffic Usage Recorder Circuit (SD-95738-01)

- 4 At interface and control circuit—
Connect ground to terminal strip terminal as
specified in Table B, Test BG
- 5 At interface and control circuit—
Disconnect ground place in Step 4.
- 6 Repeat Steps 4 and 5 for each scan lead under
test as specified in Table B, Test BG.

At circuit under test—
AR relay operates.

BH. Interface and Control Circuit (SD-28075-01)

- 4 At interface and control circuit—
Connect test probe as required, to terminal
strip terminal as specified in Table B, Test
BH.
- 5 At master test frame jack, lamp, and key
circuit—
Operate REM key.
- 6 Restore REM key operated in Step 5.
- 7 At interface and control circuit—
Disconnect test probe from terminal strip
terminal.
- 8 At interface and control circuit—
Connect ground to terminal strip terminal as
specified in Table B, Test BH.
- 9 At interface and control circuit—
Disconnect ground place in Step 8.
- 10 Repeat Steps 4 through 9 for each scan lead
under test as specified in Table B, Test BH.

At interface and control circuit—
Ground present at terminal strip terminal.

At interface and control circuit—
Ground removed from terminal strip terminal.

At circuit under test—
REM relay operates.

BI. 3A Auxiliary Processor (SD-28118-01)

**CAUTION: Refer to Section 218-799-106
for precautions to be exercised when
testing ETS offices served by a
Remote Alarm, Surveillance, and
Control System.**

SECTION 218-759-501

- | | | |
|---|--|---|
| 4 | At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BI. | At circuit under test—
Relay specified (sealed relay) in Table B, Test BI, operates.
At SSP—
LED lighted corresponding to scan lead under test, eg, scan lead LOC, LOCK LED lighted. |
| 5 | At interface and control circuit—
Disconnect ground placed in Step 4. | |
| 6 | Repeat Steps 4 and 5 for each scan lead under test as specified in Table B, Test BI. | |

BJ. Master Test Frame, Jack, Lamp, and Key Circuit (SD-25762-01) Control Functions

- | | | |
|----|---|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table B, Test BJ. | |
| 5 | At circuit under test—
Operate key specified in Table B, Test BJ. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 6 | At circuit under test—
Release key operated in Step 5. | At interface and control circuit—
Ground removed from terminal strip terminal. |
| 7 | At interface and control circuit—
Disconnect test probe from terminal strip terminal. | |
| 8 | At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BJ. | At circuit under test—
Relay specified in Table B, Test BJ operates. |
| 9 | At interface and control circuit—
Disconnect ground placed in Step 8. | |
| 10 | Repeat Steps 4 through 9 for each scan lead under test as specified in Table B, Test BJ. | |

BK. AMA Recorder Transfer Circuit (SD-28076-01)

- | | | |
|---|---|---|
| 4 | At interface and control circuit—
Connect test probe as required, to terminal strip terminal as specified in Table B, Test BK. | |
| 5 | At circuit under test—
Block operated relay specified in Table B, Test BK. | At interface and control circuit—
Ground present at terminal strip terminal. |
| 6 | At circuit under test—
Remove blocking tool placed in Step 5. | At interface and control circuit—
Ground removed from terminal strip terminal. |

7 At interface and control circuit—
Disconnect test probe from terminal strip terminal.

8 At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BK.

At circuit under test—
Relay specified in Table B, Test BK, operates.

9 At interface and control circuit—
Disconnect ground placed in Step 8.

BL. Interface and Control Circuit—(SD-28075-01)
Stuck Sender Hold Feature

4 At interface and control circuit—
Connect ground to terminal strip terminal as specified in Table B, Test BL.

At circuit under test—
Relay specified in Table B, Test BL, operates.

5 At interface and control circuit—
Disconnect ground placed in Step 4.

BM. Line Concentrator Identifier Circuit—(SD-95964-01)

4 At interface and control circuit—
Connect test probe to terminal strip terminal as specified in Table B, Test BM.

5 At line concentrator identifier under test—
Block operated LCIAR relay.

At interface and control circuit—
Ground present at terminal strip terminal.

6 Remove blocking tool placed in Step 5.

7 At interface and control circuit—
Disconnect test probe.

TABLE A

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE & CONTROL CKT		
								TERM STRIP	TERM	
A	1	ABS	ALM CKT	25671-01	FA			AA	04	ALM BAT
	2	ASMJ			AMJ				28	MJ ANN SYS
	3	ASMN			AMN				29	MN ANN SYS
	4	MJO			MJ2				00	MJ OFC
	5	MJP			PF				02	MJ PWR
	6	MNO			MN2				01	MN OFC
	7	MNP			A				03	MN PWR
	8	CMJ			CMJ				26	MJ CAR
	9	CMN			CMN				27	MN CAR
B	1	T2	MTF JLK	25762-01	T2				12	AMA MTMR OR AMA MTR BOTH REC TMR OR BDT BOTH ENC OR LAMA-C PROC MJ
	2	T3			T3				13	AMA RCDR W/O XFER OR AMA MTR REC/CONT MJ OR BDT ONE ENC OR LAMA-C DAS MJ
	3	CLI			CLI				14	CALL LINE TBL RECOR
	4	DOC			RTX				15	DOC MJ
	5	PU			PU2				06	PUA
C	1	1TR	COMB/COMP MARKER 0	25550-01 26002-01		3T TR2C 10B TR2C		AG	80 80	CM MKR (0) 1TR
	2		1						81	CM MKR (1) 1TR
	3		2						82	CM MKR (2) 1TR
	4		3						83	CM MKR (3) 1TR
	5		4						84	CM MKR (4) 1TR

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE (CONTROL CKT)		
								TERM STRIP	TERM	
	6		5						85	CM MKR (5) 1TR
	7		6						86	CM MKR (6) 1TR
	8		7						87	CM MKR (7) 1TR
	9		8						88	CM MKR (8) 1TR
	10		9						89	CM MKR (9) 1TR
	11		10					AH	80	CM MKR (10) 1TR
	12		11						81	CM MKR (11) 1TR
D	1	2TR	COMB/COMP MARKER 0	25550-01 26002-01		1T TR2C 10M TR2C		AG	70 70	CM MKR (0) 2TR
	2		1						71	CN MKR (1) 2TR
	3		2						72	CM MKR (2) 2TR
	4		3						73	CM MKR (3) 2TR
	5		4						74	CM MKR (4) 2TR
	6		5						75	CM MKR (5) 2TR
	7		6						76	CM MKR (6) 2TR
	8		7						77	CM MKR (7) 2TR
	9		8						78	CM MKR (8) 2TR
	10		9						79	CM MKR (9) 2TR
	11		10					AH	70	CM MKR (10) 2TR
	12		11						71	CM MKR (11) 2TR
E	1	LR	COMB/COMP MARKER 0	25550-01 26002-01		11T LR U LR		AG	50 50	IR LK REL
	2		1						51	

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE CONTROL CKT		
								TERM STRIP	TERM	
	3		2					52		
	4		3					53		
	5		4					54		
	6		5					55		
	7		6					56		
	8		7					57		
	9		8					58		
	10		9					59		
	11		10					AH 50		
	12		11					51		
F	1	LRI	COMP MARKER 0	26002-01		U LRI		AG 40	TR LK REL	
	2		1					41		
	3		2					42		
	4		3					43		
	5		4					44		
	6		5					45		
	7		6					46		
	8		7					47		
	9		8					48		
	10		9					49		
	11		10					AH 40		

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE & CONTROL CKT		
								TERM STRIP	TERM	
	12		11						41	
G	1	1TR	DIAL TONE MARKER 0	25550-01 26001-01		5T TR2F 10B TR2B		AH	82 82	DT MKR (0) 1TR
	2		1						83	DT MKR (1) 1TR
	3		2						84	DT MKR (2) 1TR
	4		3						85	DT MKR (3) 1TR
	5		4						86	DT MKR (4) 1TR
	6		5						87	DT MKR (5) 1TR
H	1	2TR	DIAL TONE MARKER 0	25550-01 26001-01		3T TR2F 10M TR2B		AH	72 72	DT MKR 2TR
	2		1						73	
	3		2						74	
	4		3						75	
	5		4						76	
	6		5						77	
I	1	1TR	LAMA TRANSV	25591-01 27809-01		10T 2TR 9B 2TR		AG	10 10	TV (0) 1TR
	2								11	TV (1) 1TR
	3								12	TV (2) 1TR
	4								13	TV (3) 1TR
	5								14	TV (4) 1TR
	6								15	TV (5) 1TR
	7								16	TV (6) 1TR

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE & CONTROL CKT		
								TERM STRIP	TERM	
	8								17	TV (7) 1TR
	9								18	TV (8) 1TR
	10								19	TV (9) 1TR
	1a	1TR	CAMA TRANSV	26010-01		8B 2TR		AH	12	TV (X) 1TR
	2a								13	
	3a								14	
	4a								15	
	1b	1TR	ANI TRANSV	26161-01		6B 2TR			10	TV (X) 1TR
	2b								11	
	1c	1TR	PC TRANSV	28085-01		5B TVTS			10	PCTV (0) 1TR
	2c								11	PCTV (1) 1TR
	1d	1TR	CPC TRANSV						12	CPCTV (0) 1TR
	2d								13	CPCTV (1) 1TR
J	1	2TR	LAMA TRANSV	25591-01 27809-01		8T 2TR 9M 2TR		AG	00 00	TV 2TR
	2								01	
	3								02	
	4								03	
	5								04	
	6								05	
	7								06	
	8								07	

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE & CONTROL CKT		
								TERM STRIP	TERM	
	9								08	
	10								09	
	1a	2TR	CAMA TRANSV	26010-01		8M 2TR		AH	02	CTV 2TR
	2a								03	
	3a								04	
	4a								05	
	1b	2TR	ANI TRANSV	26161-01		6M 2TR			00	ATV 2TR
	2b								01	
	1c	2TR	PC TRANSV	28085-01		4B TVTS			00	PCTV 2TR
	2c								01	
	1d	2TR	CPC TRANSV	28085-01		4B TVTS			02	CPCTV 2TR
	2d								03	
K	1	1TR	PRETRANSLATOR	25568-01		5B TR2		AF	30	PRT (0) 1TR
			0							
	2		1						31	PRT(1) 1TR
	3		2						32	PRT(2) 1TR
	4		0						33	IR PRT(0) 1TR
	5		1						34	IR PRT(1) 1TR
	6		2						35	IR PRT(2) 1TR
	7		0						36	IDDD PRT(0) 1TR
	8		1						37	IDDD PRT(1) 1TR
L	1	2TR	PRETRANSLATOR	25568-01		3M TR2		AF	20	PRT 2TR

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE CONTROL CKT		
								TERM STRIP	TERM	
			0							
	2		1						21	
	3		2						22	
	4		0						23	IR PRT 2TR
	5		1						24	
	6		2						25	
	7		0						26	IDDD PRT 2TR
	8		1						27	
M	1	TRMJ	TROUBLE RDR CONTROL	25572-01		5B MC0		AA	16	TBL RCDR MJ
	2	TRMN			WAR				17	TBL RCDR MN
N	1	CS	COIN SUPV.	25736-01	AL				18	COIN SUPV MJ
O	1	AM	AMRST	25680-01		7B XM			22	AUTO MON MN
P	1	LIT	LINE INSUL TST	25796-01	TA				20	LIT MN
Q	1	RAL	DT SPD REG.	96403-01	AL			AA	25	DTSR MN
R	1	TURA	TFC USG REC	95738-01	TBL				24	TUR MN
S	1	BAT	MTCE DT	28111-01		4B ACO			48	MDT MJ
T	1	LL	LNLD CONT	96387-01		6B AB/AC			08	LN LD CONT MJ
U	1	MFS	MF SUPP	95391-01	ALM				09	MF SUP MJ
V	1	MR	MR SUPP	25770-01		2B RP			10	MR SUP MJ
W	1	LIP	LN ID SUPP	27700-01		2M TR			11	LN ID SUP MJ
X	1	PBX MJ	EXT ALM	95484-01		9T A1			30	PBX MJ
	2	PBX MN				7T B1			30	PBX MN

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE (CONTROL QKT)		
								TERM STRIP	TERM	
	3	CDO MJ				9T A1			32	CDO MJ
	4	CDO MN				7T B1			33	CDO MN
	5	CPA					1B/2B A/B		05	CA PROT MJ
Y	1	MJM	PBX AIOD	1C006-01	FA				36	PBX AIOD MJ
	2	MNM		1C236-01	MNA				43	PBX AIOD MN
Z	1	1AL	1A CONC	94815-01	CAL				38	LC 1A LOC MJ
	2	1AR			RAL				39	LC 1A REM MJ
AA	1	2AL	2A CONC	94815-01	FA				40	LC 2A LOC MJ
	2	2AR			FA				41	LC 2A REM MJ
AB	1	DMB	ALL MKR TV BSY	25695-01	B2			AB	09	DTM LD ALM
	2	CMB					B2	AA	89	CM LD ALM
	3	TVB					B2	AB	27	CTV/CPCTV LD ALM
	4	TVB					B2		28	TV LD ALM
	5	TVB					B2		29	ATV/PCTV LD ALM
AC	1	ORB	TFC REG	25890-01	BY				59	OR LD ALM
				25892-01	B				59	
	2	IRB			E				58	IR LD ALM
					A				58	
	3	CSB		25892-01	CB 1				57	CS LD ALM
AD	1	SGB	SNDR GP BUSY	25500-01	A				56	OS LD ALM
				27638-01	ND				56	
				25890-01	E				56	

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE CONTROL CKT		
								TERM STRIP	TERM	
	2	DP		25500-01		7B H			50	DP SDR GP BUSY
				27638-01		7B H			50	
	3	MF				7B H			51	MF SDR GP BUSY
						7B H			51	
	4	RP				7B H			52	RP SDR GP BUSY
						7B H			52	
	5	PCI				7B H			53	PCI SDR GP BUSY
	6	IMG				7B H			54	IMG SDR GP BUSY
						7B H			54	
AE	1	MAA1	101ESS MTC	1 H052-01	MJ			AA	34	101 ESS MJ
	2	MIA1		1 H052-01	MN				35	101 ESS MN
AF	1	CRT/T2	3A PROC	28118-01		1M CRT		AA	12	ETS CRITICAL
	2	MJ1/T3				1M MJ			13	ETS MJ
	3	MN1					2M MINOR	AB	72	ETS MN
AG	1	WDT-0	ETS PDI	28114-01		8B OSC-0			60	DAS GP (0) WD TMR
	2	WDT-1				1			61	DAS GP (1) WD TMR
	3	WDT-2				2			62	DAS GP (2) WD TMR
	4	WDT-3				3			63	DAS GP (3) WD TMR
	5	WDT-4				4			64	DAS GP (4) WD TMR
	6	WDT-5				5			65	DAS GP (5) WD TMR
	7	WDT-6				6			66	DAS GP (6) WD TMR
	8	WDT-7				7			67	DAS GP (7) WD TMR

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE CONTROL CKT		
								TERM STRIP	TERM	
	9	WDT-8				8			68	DAS GP (8) WD TMR
	10	WDT-9				9			69	DAS GP (9) WD TMR
	11	WDT-10				10			70	DAS GP (10) WD TMR
	12	WDT-11				11			71	DAS GP (11) WD TMR
AH	1	AIOD 0	ETS PDI		28114-01	5M BMJ0			77	ETS AIOD (0) STUCK
	2	AIOD 1				5M BMJ1			78	ETS AIOD (1) STUCK
AI	1	PCTV-0	ANI PCTV	28085-01	TMR1				73	ANI PCTV(0) STUCK
	2	PCTV-1							74	ANI PCTV(1) STUCK
	3	CPCTV-0	CAMA PCTV						75	CAMA PCTV(0) STUCK
	4	CPCTV-1							76	CAMA PCTV(1) STUCK
AJ	1	PS	PS ALM CKT	26135-01	A			AA	07	PERM SIG
				25815-01	C				07	
AK	1	TNS	MTF JLK	25762-01	REM KEY			AC	99	ALM XFERRED
	2	CCLG			CCT, CLPT CGT KEYS			AA	42	MKR GLC TST OFF
AL	1	SP	ALM SNDG	95417-01	TR KEY			AC	97	ALM SDG ON
AM	1	RC	RCDR TRANS.	28076-01		12M T00		AA	21	AMA EM RCDR W/T
	2	ERC					3B/4BNPA		19	AMA EM RCDR MJ
	3	TR			TR				23	AMA RCDR XFERRED
AN	1	PC	COMB/COMP MARKER 0	25550-01 26002-1	CKG 8 CKG 7			AG	60 60	[CM MKR USAGE]
	2		1						61	
	3		2						62	

TABLE A (Contd)

ALARM/STATUS LEADS										
TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO.	TEST ACTION			VERIFICATION		ALARM OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					BLOCK RELAY OPERATED	CONNECT GROUND RELAY CONTACT	SHORT CIRCUIT RELAY CONTACTS	READ GROUND AT INTERFACE & CONTROL CKT		
								TERM STRIP	TERM	
	4		3					63		
	5		4					64		
	6		5					65		
	7		6					66		
	8		7					67		
	9		8					68		
	10		9					69		
	11		10				AH	60		
	12		11					61		
AO	1	PC	DIAL TONE MARKER 0	25550-02 26001-01	HGR CKG 1			AH 62 62	[DT MKR USAGE]	
	2		1					63		
	3		2					64		
	4		3					65		
	5		4					66		
	6		5					67		
AP	1	RTAL	EDTSR	3B504-01		5B ALM CTF		AA 44	EDTSR MN	
AQ	1	MNM	TRANS CONN	99320-01		2M QTR		AA 37	PBX AIOD CONN MN	
AR	1	C	L CONC ID	95964-01	FA			AA 49	LC IDENT TO	
AS	1	MJ	NO 1 TRK CONC	97595-01	MJO			AA 47	No 1 TRK CONC MJ	
	2	MN			MNI			45	No 1 TRK CONC MN	
	3	PS			OS			46	No 1 TRK CONC PS	

TABLE B
COMMAND/STATUS

TEST STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO	TEST ACTION			VERIFICATION			COMMAND OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
				INSERT MB PLUG	OPERATE KEY	CONNECT GROUND	READ GROUND @ INTERFACE & CONTROL CIRCUIT			
							TERM STRIP	TERM	RELAY OPERATED	
BA 1	MB	DIAL TONE MKR	25550-01 26001-01	DT0 MB JK			AC	13		DT MKR (0) MB
1A	MB					@	AD	13	MB(0)	RMV DT (0)
2	MB			DT1 MB JK			AC	14		DTMKR (1) MB
2A	MB					@	AD	14	MB(1)	RMV DT(1)
3	MB			DT2 MB JK			AC	15		DT MKR(2) MB
3A	MB					@	AD	15	MB(2)	RMV DT(2)
4	MB			DT3 MB JK			AC	16		DT MKR (3) MB
4A	MB					@	AD	16	MB(3)	RMV DT(3)
5	MB			DT4 MB JK			AC	17		DT MKR (4) MB
5A	MB					@	AD	17	MB(4)	RMV DT(4)
6	MB			DT5 MB JK			AC	18		DT MKR (5) MB
6A	MB					@	AD	18	MB(5)	RMV DT(5)
BB 1	MB	COMB/COMP MARKER	25550-01 26002-01	CM0 MB JK			AC	00		CM MKR (0) MB
1A	MB					@	AD	00	MB(0)	RMV CM(0)
2	MB			CM1 MB JK			AC	01		CM MKR (1) MB
2A	MB					@	AD	01	MB(1)	RMV CM(1)
3	MB			CM2 MB JK			AC	02		CM MKR (2) MB
3A	MB					@	AD	02	MB(2)	RMV CM(2)
4	MB			CM3 MB JK			AC	03		CM MKR(3) MB
4A	MB					@	AD	03	MB(3)	RMV CM(3)
5	MB			CM4 MB JK			AC	04		CM MKR (4) MB
5A	MB					@	AD	04	MB(4)	RMV CM(4)
6	MB			CM5 MB JK			AC	05		CM MKR(5) MB

TABLE B (Contd)
COMMAND/STATUS

TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO	TEST ACTION			VERIFICATION			COMMAND OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					INSERT MB PLUG	OPERATE KEY	CONNECT GROUND	READ GROUND@ INTERFACE & CONTROL CIRCUIT			
								TERM STRIP	TERM	RELAY OPERATED	
	6A	MB					@	AD	05	MB(5)	RMV CM(5)
	7	MB			CM6 MB JK			AC	06		CM MKR (6)MB
	7A	MB					@	AD	06	MB(6)	RMV CM(6)
	8	MB			CM 7 MB JK			AC	07		CM MKR (7) MB
	8A	MB					@	AD	07	MB(7)	RMV CM(7)
BB	9	MB	COMB/COMP MARKER	25550-01 26002-01	CM8 MB JK			AC	08		CM MKR (8) MB
	9A	MB					@	AD	08	MB(8)	RMV CM(8)
	10	MB			CM9 MB JK			AC	09		CM MKR (9) MB
	10A	MB					@	AD	09	MB(9)	RMV CM(9)
	11	MB			CM10 MB JK			AC	10		CM MKR (10) MB
	11A	MB					@	AD	10	MB(10)	RMV CM(10)
	12	MB			CM11 MB JK			AC	11		CM MKR (11) MB
	12A	MB					@	AD	11	MB (11)	RMV CM (11)
BC	1	MB	TRANSVERTER CIRCUIT	25591-01 26010-01 26161-01 27809-01	TV0 MB JK			AC	26		TV (0) MB
	1A	MB					@	AD	26	RB(0)	RMV TV(0)
	2	MB			TV1 MB JK			AC	27		TV (1) MB
	2A	MB					@	AD	27	RB(1)	RMV TV(1)
	3	MB			TV2 MB JK			AC	28		TV(2) MB
	3A	MB					@	AD	28	RB (2)	RMV TV(2)
	4	MB			TV3 MB JK			AC	29		TV (3) MB

TABLE B (Contd)

COMMAND/STATUS

TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO	TEST ACTION			VERIFICATION			COMMAND OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					INSERT MB PLUG	OPERATE KEY	CONNECT GROUND	READ GROUND @ INTERFACE & CONTROL CIRCUIT			
								TERM STRIP	TERM	RELAY OPERATED	
	4A	MB					@	AD	29	RB(3)	RMV TV(3)
	5	MB			TV4 MB JK			AC	30		TV (4) MB
	5A	MB					@	AD	30	RB(4)	RMV TV(4)
	6	MB			TV5 MB JK			AC	31		TV(5) MB
	6A	MB					@	AD	31	RB(5)	RMV TV(5)
	7	MB			TV6 MB JK			AC	32		TV (6) MB
	7A	MB					@	AD	32	RB (6)	RMV TV (6)
	8	MB			TV7 MB JK			AC	33		TV (7) MB
	8A	MB					@	AD	33	RB(7)	RMV TV(7)
	9	MB			TV8 MB JK			AC	34		TV(8) MB
	9A	MB					@	AD	34	RB(8)	RMV TV(8)
	10	MB			TV9 MB JK			AC	35		TV (9) MB
	10A	MB					@	AD	35	RB (9)	RMV TV (9)
BD	1	MB	OR PRT	25568-01	PRT0 MB JK			AC	39		PRT (0) MB
	1A	MB					@	AD	39	MB(0)	RMV PRT (0)
	2	MB			PRT1 MB JK			AC	40		PRT (1) MB
	2A	MB					@	AD	40	MB(1)	RMV PRT(1)
	3	MB			PRT2 MB JK			AC	41		PRT (2) MB
	3A	MB					@	AD	41	MB(2)	RMV PRT(2)
	4	MB	IR PRT		IR PRTO MB JK			AC	42		IR PRT(0) MB
	4A	MB					@	AD	42	MB(0)	RMV IRP(0)
	5	MB			IR PRT1 MB JK			AC	42	MB(0)	IR PRT (1) MB

TABLE B (Contd)
COMMAND/STATUS

TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO	TEST ACTION			VERIFICATION			COMMAND OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					INSERT MB PLUG	OPERATE KEY	CONNECT GROUND	READ GROUND @ INTERFACE & CONTROL CIRCUIT			
								TERM STRIP	TERM	RELAY OPERATED	
	5A	MB					@	AD	04	MB(1)	RMV IRP(1)
	6	MB			IR PRT 2 MB JK			AC	44		IR PRT (2) MB
	6A	MB					@	AD	44	MB(2)	RMV IRP(2)
	7	MB	IDDD PRT		IDDD PRT0 MB JK			AC	45		IDDD PRT(0) MB
	7A	MB					@	AD	45	MB(0)	RMV IDDD P (0)
	8	MB			IDDD PRT 1 MB JK			AC	46		IDDD PRT(1) MB
	8A	MB					@	AD	46	MB(1)	RMV IDDDP (1)
BE	1	MB	TBL RCDR	25572-01	TRMB JK			AC	25		TBL RCDR MB
	1A	MB					@	AD	25	ROS	TRMB
BF	1	RS	LIT	25796-01		TS		AC	12		LIT TS
	1A	RS					@	AD	12	RS	RMV LIT
BG	1	AR	TUR	95738-01			@	AD	47	AR	TURAR
BH	1	REM	INT&CONT	28075-01		REM		AC	99		ALM XFERED
	1A	REM					@	AD	99	REM	REM
	2	CTL CTL					@	AD AC	97 95	LAMP CTL	CTL CTL ACT BY CENTRAL
	3	CAL CAL					@	AD AC	98 96	LAMP CAL	CALL CALL CENTRAL
	4	BGLC					@	AD AC	36 36	B	GLC MB GLC TEST
BI	1	LOC	3A PROC	28118-01			@	AD	52	LOCK	ETS-LOC
	2	FOR					@	AD	53	FORCE	ETS-FOR
	3	SEL 0					@	AD	54	SEL 0	ETS-SEL 0
	4	SEL 1					@	AD	55	SEL 1	ETS-SEL 1

TABLE B (Contd)

COMMAND/STATUS

TEST	STEP	SCAN LEAD UNDER TEST	LOCAL OFFICE SIGNAL SOURCE CIRCUIT	SD NO	TEST ACTION			VERIFICATION			COMMAND OR STATUS CONDITION INDICATED AT CENTRAL AND LOCAL OFFICE
					INSERT MB PLUG	OPERATE KEY	CONNECT GROUND	READ GROUND@ INTERFACE & CONTROL CIRCUIT			
								TERM STRIP	TERM	RELAY OPERATED	
	5	ENA					@	AD	59	ENABLE	ETS-ENA
	6	MEM					@	AD	58	MEMREL	ETS-MEM
	7	PA0	3A PROC	28118-01			@	AD	57	PAOFDA	ETS-PA0
	8	INT					@	AD	56	INTEXC	ETS-INIT
	9	TTYI					@	AD	48	TTY INT	ETS-TTYI
BJ	1	CLR	MTF JLK	25762-01		CLR		AC	24		LK REL TBL CD CAN
	1A	CLR					@	AD	24	CLR	CLR
	2	RT0				RT0	@	AC	19		RT TFR (0) ACT
	2A	RT0					@	AD	19	RT0	RT(0)
	3	RT1				RT1		AC	20		RT TFR(1) ACT
	3A	RT1					@	AD	20	RT1	RT(1)
	4	RT2				RT2	@	AC	21		RT TFR (2) ACT
	4A	RT2					@	AD	21	RT2	RT (2)
	5	RT3				RT3		AC	22		RT TFR(3) ACT
	5A	RT3					@	AC	22	RT(3)	RT(3)
	6	RT4				RT4		AC	23		RT TFR (4) ACT
	6A	RT4					@	AD	23	RT(4)	RT(4)
BK	1	TR	RCDR TRANS	28076-01		TR RELAY		AA	23		AMA RCDR XFERED
	2	CT					@	AD	38	CT	RMV AMA RCDR
BL	1	SSH	INT&CONT	28075-01			@	AD AC	37 37	SSH	SSH SSH ACT
BM	1	CIAR	LN CONC IDENT	95964-01			@	AD AC	49 49	AR1	LCIAR LCIAR LATCHED

